

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:) Confirmation No.: 5002
Keith W. Reiss)
) Group Art Unit: 2884
)
Application Number: 10/607,572) Examiner: Taningco, Marcus H.
)
Filed: June 27, 2003)
)
For: SPECTROSCOPIC SIGNAL PROCESSING METHODOLOGY

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

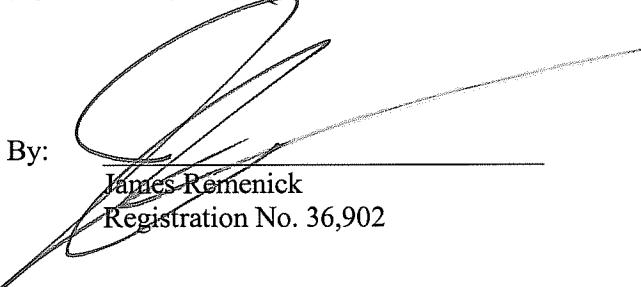
Sir:

In accordance with 37 C.F.R. §§ 1.97 and 1.98, and in compliance with the duty of disclosure set forth in 37 C.F.R. § 1.56, applicants are submitting herewith the attached Form PTO/SB08a/b for consideration and to be made of record herein by the U.S. Patent and Trademark Office in the above-captioned application. In accordance with 37 C.F.R. § 1.98(a)(2)(ii) copies of the U.S. patents and U.S. patent application publications are not enclosed.

This Information Disclosure Statement is along with a Request for Continued Examination. Therefore, it is respectfully submitted that no fee is required for consideration of this information. However, in the event any fee is deemed necessary, the Commissioner is authorized to charge the undersigned's Deposit Account No. 14-1437.

Respectfully submitted,

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Dated: July 25, 2007

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Substitute for form 1449A/B/PTO				Complete if Known	
				Application Number	10/607,572
				Filing Date	June 27, 2003
				First Named Inventor	Keith W. Reiss
				Art Unit	2884
				Examiner Name	Taningco, Marcus H.
Sheet	1	of	2	Attorney Docket Number	8107.003.US

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			
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A2	US-2,524,290		10-1950	HERSHBERGER WILLIAM D	
A3	US-2,792,548		05-1957	HERSHBERGER WILLIAM D	
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Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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NON PATENT LITERATURE DOCUMENTS					
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			^{T²}
	C1	Carter, R. L. et al., Physical Review 1947, 72, 1265-1266.			
	C2	Costain, C. C., Canadian Journal of Physics 1957, 35, 241-247.			

Examiner Signature	Date Considered
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	C6	Schiak, B. et al, Conference Proceedings – European Microwave Conference 7 th 1977, 251-255, Publisher: Microwave Exhibitions Publications Ltd., Sevenoaks, England.	
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